

Contribution ID: 718

Type: Invited Speaker / Conférencier(ère) invité(e)

(I) Quantum Technologies in Sensing, Imaging, and Metrology: From the Laboratory to Near-Term Commercial Applications

Tuesday 8 June 2021 11:05 (30 minutes)

This keynote will provide a high-level overview of the current state-of-the-art in quantum technologies and their applications to sensing, imaging and metrology. I will start with a brief historical view about how National Metrology Laboratories like NIST and NRC-Canada have used these technologies for years. I will then transition to some near-term commercial applications before returning to a long-term view of the future applications of these quantum technologies to National Metrology Laboratories, society, and basic science.

Author: Dr WILLIAMS, Carl (Deputy Director, Physical Measurement Laboratory National Institute of Standards and Technology)

Presenter: Dr WILLIAMS, Carl (Deputy Director, Physical Measurement Laboratory National Institute of Standards and Technology)

Session Classification: TS-7 Sensors and Metrology Symposium (NRC) / Symposium sur les capteurs et la métrologie (CNRC)

Track Classification: Symposium Day (NRC) - Physics for the next generation of sensors and metrology (NRC)